

L Number	Hits	Search Text	DB	Time stamp
-	6	("3752952" "3409799").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 12:52
-	18	"3752952" "3409799"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:05
-	1272	electron adj beam and (beam near4 profile)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:05
-	553	(electron adj beam and (beam near4 profile)) and (target or reticle)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:07
-	31	((electron adj beam and (beam near4 profile)) and (target or reticle)) and back adj scatter\$2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:05
-	48	(electron adj beam and (beam near4 profile)) and back adj scatter\$2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 21:25
-	29	(electron adj beam and test adj pattern) and back adj scatter\$2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 19:18

-	14612	electron adj beam and weld\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 21:25
-	90	electron adj beam and weld\$3 and backscatter\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:33
-	19	(electron adj beam and weld\$3 and backscatter\$3) and spot adj (size or shape)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:42
-	90	(electron adj beam) and weld\$3 and backscatter\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:33
-	0	(electron adj beam and weld\$3 and backscatter\$3) and spot adj (profile or uniformity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:42
-	2	(electron adj beam and weld\$3 and backscatter\$3) and beam adj (profile or uniformity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 16:08
-	911	electron adj beam and test adj pattern	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:33
-	23	(electron adj microscope and test adj pattern) and back adj scatter\$2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 18:50

-	2996	(electron adj microscope and slit)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 19:26
-	59	(electron adj microscope and slit) and beam adj profile	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 19:32
-	4	(electron adj microscope and slit) and (electron near4 beam adj profile)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:24
-	10030	(electron adj microscope and (needle or raised))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:26
-	3778	(electron adj microscope and (needle))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:27
-	72	(electron adj microscope and (needle near4 tungsten))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:27
-	56	(electron adj microscope and (needle near2 tungsten))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:28
-	0	electron adj beam and (test adj pattern) near4 needle	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:34

-	0	electron adj beam and (test adj pattern) near4 raised	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:35
-	12080	electron adj beam and grid	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:35
-	1707	electron adj beam and grid and distortion	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 14:35
-	16	electron adj beam and grid and distortion near measurement	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:16
-	17	"6204509"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:02
-	64	electron adj beam and grid and distortion WITH measurement	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:17
-	16	(electron adj beam and weld\$3 and backscatter\$3) and image and target	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 15:51
-	31	(electron adj beam and weld\$3 and backscatter\$3) and image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 15:57

-	6	(electron adj beam and machining and backscatter\$3) and beam adj (profile or uniformity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 16:38
-	0	electron adj beam WITH milling and back-scattered	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 16:14
-	13	(electron adj beam WITH milling) and backscattered	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 16:34
-	5087	(electron adj beam)and beam near control\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 16:35
-	10367	(electron adj beam)and beam near2 control\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 16:36
-	3751	(electron adj beam)and beam adj control\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 16:36
-	2043	(electron adj beam) and beam adj control	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 16:36
-	0	((electron adj beam and weld\$3 and backscatter\$3) and image) and ((electron adj beam) and beam adj control)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:19

-	362	electron adj beam WITH milling	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 16:57
-	71	(electron adj beam WITH milling) and (backscattered or secondary)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 17:05
-	36	(electron adj beam WITH milling) and (backscattered or secondary) and measur\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 17:28
-	14	(electron adj beam WITH repair) and (backscattered or secondary) and measur\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/07 17:28
-	2354	((electron adj beam and weld\$3) and image)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:20
-	71	((electron adj beam and weld\$3) and image)) and segmented	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:28
-	1	((electron adj beam and weld\$3) and image)) and sensor adj ring	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:31
-	21	((electron adj beam and weld\$3) and image)) and sensor WITH ring	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:31

-	1	(US-3409799-\$ or US-3409799-\$).did.	USOCR	2004/10/11 15:37
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-	750	weld near4 image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:42
-	30	weld near4 image and electron adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:43
-	5	weld near4 image and electron adj beam and segment\$2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:43
-	2	(electron adj microscope and test adj pattern) and usaf	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:55
-	25	(electron adj microscope) and usaf	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 15:59
-	195	segmented adj detector	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 16:00
-	25	segmented adj detector and electron adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 16:00
-	5	"4794259"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 21:23

-	3129	(250/397 250/398 250/307 216/39).cccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 21:24
-	14	((250/397 250/398 250/307 216/39).cccls.) and (electron adj beam and (beam near4 profile)) and back adj scatter\$2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 21:25
-	68	((250/397 250/398 250/307 216/39).cccls.) and electron adj beam and weld\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 21:26
-	35	((250/397 250/398 250/307 216/39).cccls.) and electron adj beam and weld\$3) and image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/11 21:26